

Abstracts

Determining Timing for Isothermal Pulsed-Bias S-Parameter Measurements

A. Parker, J. Scott, J. Rathmell and M. Sayed. "Determining Timing for Isothermal Pulsed-Bias S-Parameter Measurements." 1996 MTT-S International Microwave Symposium Digest 96.3 (1996 Vol. III [MWSYM]): 1707-1710.

S-parameters measured under pulsed conditions are shown to vary from their steady-state values with pulse measurement width and pulse repetition rate. A method is presented for determining suitable timing for isothermal, pulsed-bias, pulsed-RF, S-parameter measurement of GaAs devices. Variation of S-parameters with wafer temperature and with measurement duration and duty cycle are correlated.

[Return to main document.](#)

Click on title for a complete paper.